

	Type	L #	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition	Errors
1	BRS	L1	2927	machin\$4 and vision and threshold\$4 and imag\$4	USPAT	2004/03/12 10:20			0
2	BRS	L2	1460	1 and focus\$4	USPAT	2004/03/12 10:42			0
3	BRS	L3	1434	2 and (calculat\$4 or comput\$4 or measur\$5)	USPAT	2004/03/12 10:41			0
4	BRS	L4	1073	3 and memor\$4	USPAT	2004/03/12 10:22			0
5	BRS	L5	1317	3 and (buffer or stor\$4 or memor\$4)	USPAT	2004/03/12 10:41			0
6	BRS	L6	1023	5 and improv\$4	USPAT	2004/03/12 10:51			0
7	BRS	L7	716	6 and pixel\$4	USPAT	2004/03/12 10:47			0
8	BRS	L8	670	7 and compar\$4	USPAT	2004/03/12 10:44			0
9	BRS	L9	476	8 and constant\$4	USPAT	2004/03/12 10:34			0
10	BRS	L10	142	9 and (averag\$4 near4 valu\$4)	USPAT	2004/03/12 10:41			0
11	BRS	L11	69	10 and accumulat\$4	USPAT	2004/03/12 10:48			0
12	BRS	L12	66	11 and (display\$4 or monitor\$5)	USPAT	2004/03/12 10:41			0
13	BRS	L13	61	12 and filter\$4	USPAT	2004/03/12 10:42			0
14	BRS	L14	61	13 and siz\$4	USPAT	2004/03/12 10:36			0
15	BRS	L15	58	14 and shap\$5	USPAT	2004/03/12 10:36			0
16	BRS	L16	54	15 and add\$4	USPAT	2004/03/12 10:42			0

	Type	L #	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition	Errors
17	BRS	L17	54	16 and result\$4	USPAT	2004/03/12 10:37			0
18	BRS	L18	41	17 and subtract\$4	USPAT	2004/03/12 10:47			0
19	BRS	L19	13	18 and rectangl\$5	USPAT	2004/03/12 10:38			0
20	BRS	L20	12	19 and column	USPAT	2004/03/12 10:38			0
21	BRS	L21	12	20 and row	USPAT	2004/03/12 10:39			0
22	BRS	L22	11	21 and logic\$5	USPAT	2004/03/12 10:40			0
23	BRS	L23	2657	machine near4 vision	USPAT	2004/03/12 10:46			0
24	BRS	L24	349	23 and (averag\$4 near4 valu\$4)	USPAT	2004/03/12 10:43			0
25	BRS	L25	2417	23 and (calculat\$4 or comput\$4 or measur\$5)	USPAT	2004/03/12 10:46			0
26	BRS	L26	1973	25 and (buffer or stor\$4 or memor\$4)	USPAT	2004/03/12 10:47			0
27	BRS	L27	1445	26 and (display\$4 or monitor\$5)	USPAT	2004/03/12 10:47			0
28	BRS	L28	758	27 and filter\$4	USPAT	2004/03/12 10:42			0
29	BRS	L29	303	28 and subtract\$4	USPAT	2004/03/12 10:42			0
30	BRS	L30	239	29 and add\$4	USPAT	2004/03/12 10:48			0
31	BRS	L31	144	30 and focus\$4	USPAT	2004/03/12 10:42			0
32	BRS	L32	50	31 and (averag\$4 near4 valu\$4)	USPAT	2004/03/12 10:43			0

	Type	L #	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition	Errors
33	BRS	L33	9	32 and defocus\$4	USPAT	2004/03/12 10:44			0
34	BRS	L34	55	28 and defocus\$4	USPAT	2004/03/12 10:47			0
35	BRS	L35	43	34 and improv\$4	USPAT	2004/03/12 10:44			0
36	BRS	L36	39	35 and compar\$4	USPAT	2004/03/12 10:46			0
37	BRS	L37	2510	machine adj2 vision	USPAT	2004/03/12 10:51			0
38	BRS	L38	2304	37 and (calculat\$4 or comput\$4 or measur\$5)	USPAT	2004/03/12 10:46			0
39	BRS	L39	1745	38 and compar\$4	USPAT	2004/03/12 10:46			0
40	BRS	L40	89	39 and defocus\$4	USPAT	2004/03/12 10:53			0
41	BRS	L41	74	40 and (display\$4 or monitor\$5)	USPAT	2004/03/12 10:52			0
42	BRS	L42	65	41 and (buffer or stor\$4 or memor\$4)	USPAT	2004/03/12 10:47			0
43	BRS	L43	36	42 and subtract\$4	USPAT	2004/03/12 10:53			0
44	BRS	L44	31	43 and pixel\$4	USPAT	2004/03/12 10:52			0
45	BRS	L45	18	44 and add\$4	USPAT	2004/03/12 10:48			0
46	BRS	L46	11	45 and accumulat\$4	USPAT	2004/03/12 10:50			0
47	BRS	L47	11	46 and improv\$4	USPAT	2004/03/12 10:51			0

	Type	L #	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition	Errors
48	BRS	L48	298	(machine adj2 vision) and accumulat\$4 and imag\$4 and compar\$4 and improv\$5	USPAT	2004/03/12 10:52			0
49	BRS	L49	216	48 and (display\$4 or monitor\$5)	USPAT	2004/03/12 10:52			0
50	BRS	L50	184	49 and pixel\$4	USPAT	2004/03/12 10:52			0
51	BRS	L52	109	50 and focus\$4	USPAT	2004/03/12 10:53			0
52	BRS	L53	67	52 and subtract\$4	USPAT	2004/03/12 10:53			0

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[1](#) [2](#) [Next](#)
